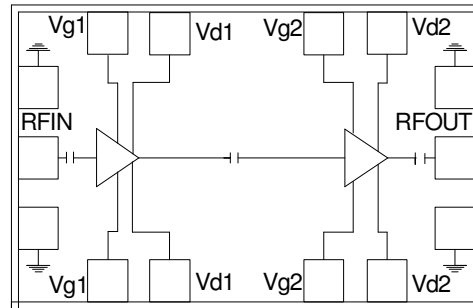


## 8 – 10 GHz 4 Watt Power Amplifier

### Features

- ◆ Frequency Range : 8 – 10GHz
- ◆ 36.5 dBm Psat
- ◆ 14 dB Power gain
- ◆ 25% PAE
- ◆ High IP3
- ◆ Input Return Loss > 9 dB
- ◆ Output Return Loss > 9 dB
- ◆ Dual bias operation
- ◆ DC decoupled input and output
- ◆ 0.5  $\mu\text{m}$  InGaAs pHEMT Technology
- ◆ Chip dimension: 5.3 x 2.8 x 0.1 mm

Functional Diagram



### Typical Applications

- ◆ RADAR
- ◆ Military & space
- ◆ LMDS, VSAT

### Description

The AMT2144091 is a X-band Power amplifier with 36.5dBm power output. The PA uses 2 stages of amplification and operates in 8 – 10 GHz frequency range. The PA features 14 dB of gain with input and output return losses of 9 dB respectively. The PA has a high IP3 of 45dBm and 25% PAE. This feature enables it to be used in the applications requiring efficiency along with linearity. The chip operates with dual bias supply voltage. The die is fabricated using a reliable 0.5 $\mu\text{m}$  InGaAs pHEMT technology. The Circuit grounds are provided through vias to the backside metallization.

### Absolute Maximum Ratings <sup>(1)</sup>

Parameter	Absolute Maximum	Units
Drain bias voltage (Vd)	+10	volts
Drain current (Id)	2.3	A
RF input power (RFin at Vd=9V)	33	dBm
Operating temperature	-50 to +85	$^{\circ}\text{C}$
Storage Temperature	-65 to +150	$^{\circ}\text{C}$

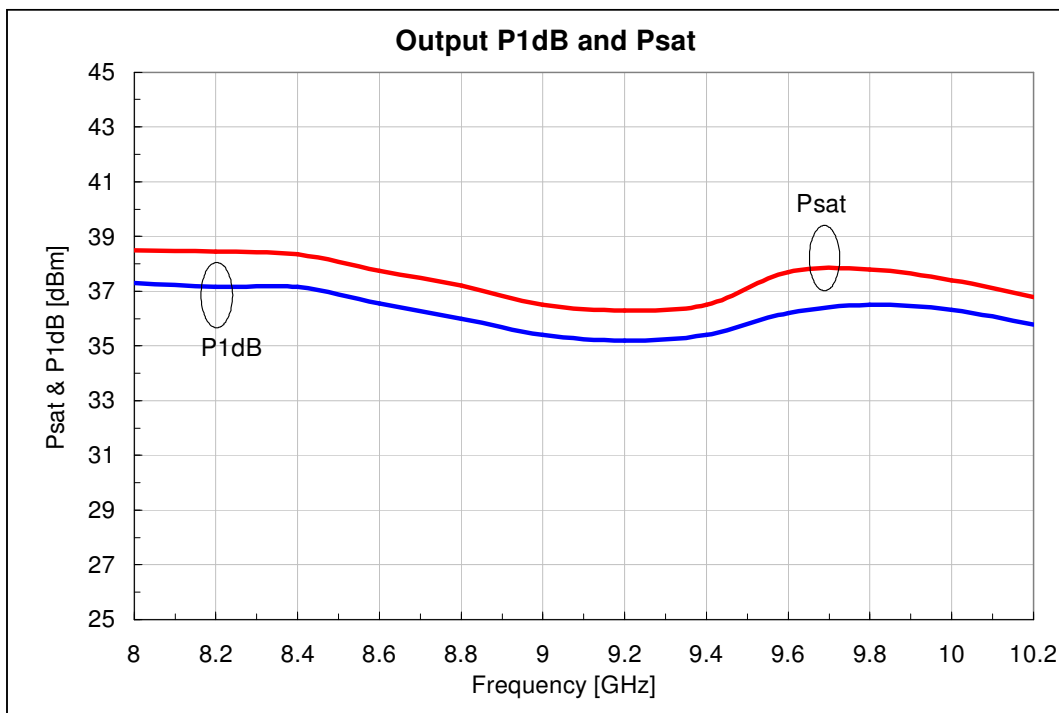
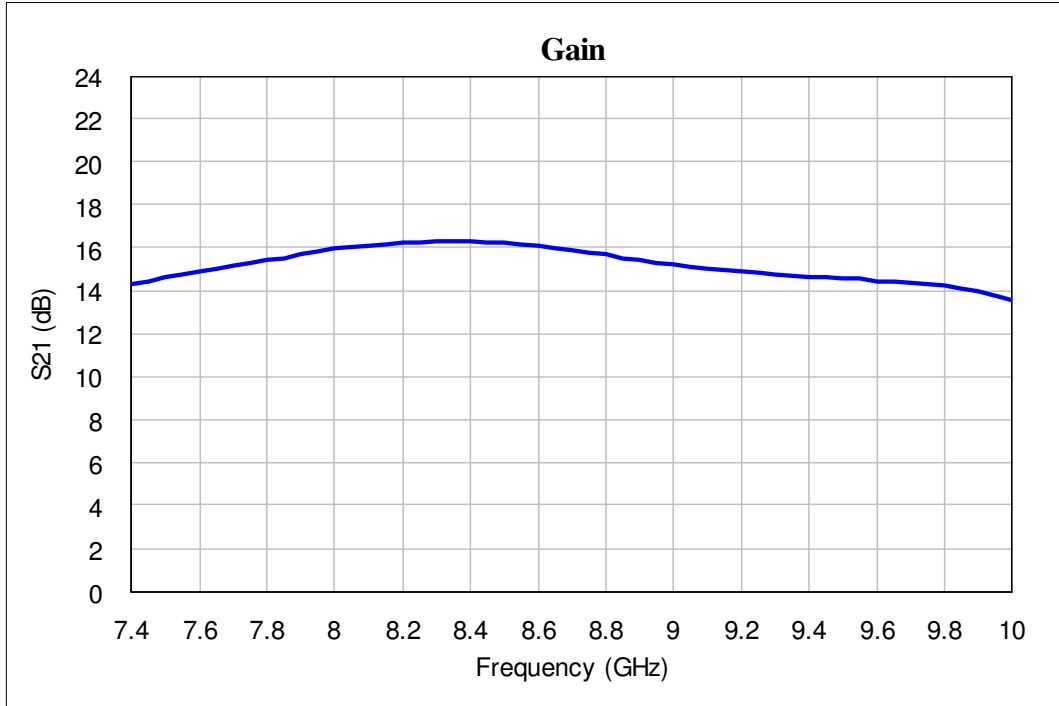
1. Operation beyond these limits may cause permanent damage to the component

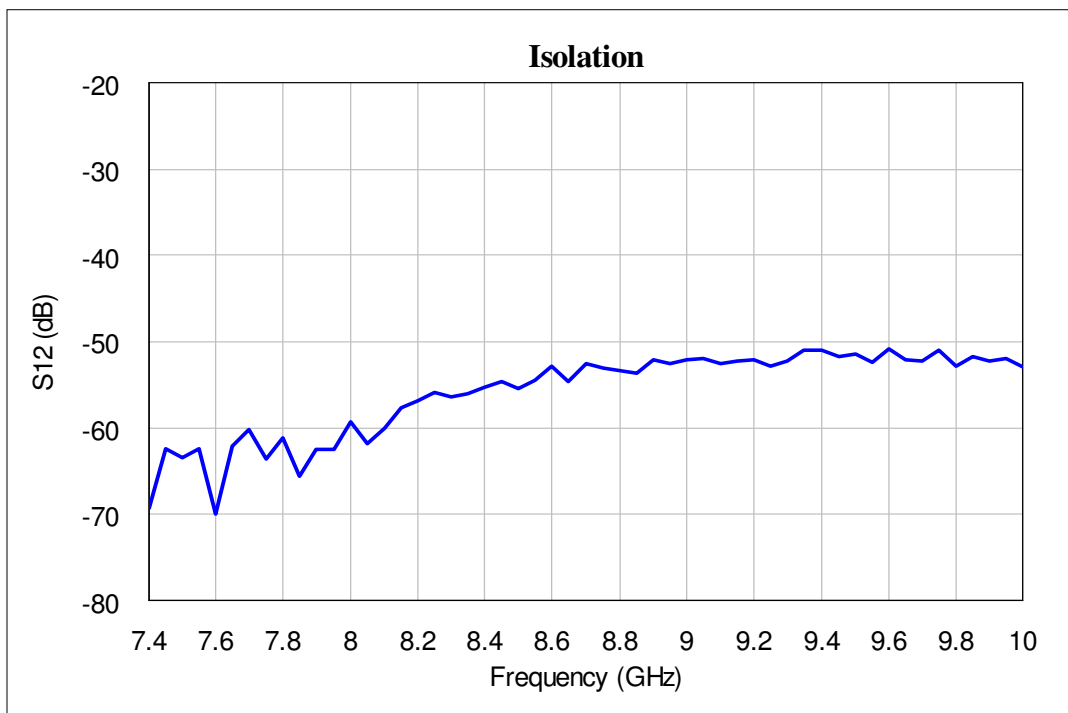
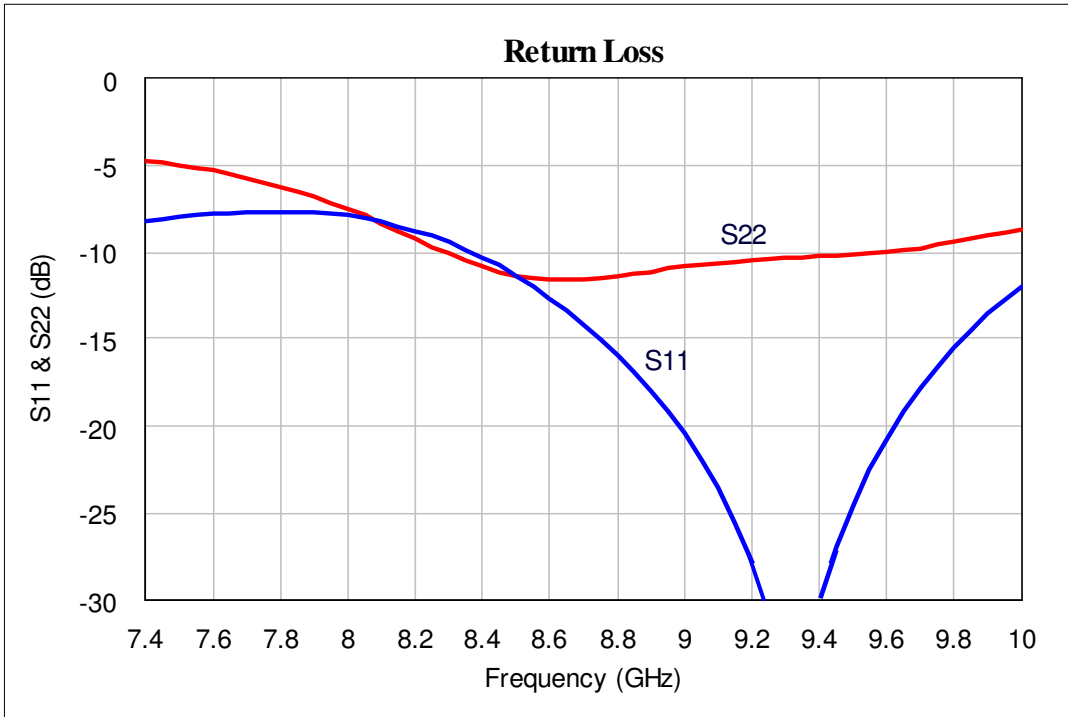
**Electrical Specifications <sup>(1)</sup> @ T<sub>A</sub> = 25 °C, V<sub>d1</sub> = V<sub>d2</sub> = 8V, V<sub>g1</sub> = V<sub>g2</sub> = -1.1V  
Z<sub>o</sub> = 50 Ω**

Parameter	Typ.	Units
Frequency Range	8 – 10	GHz
Gain	14	dB
Gain Flatness	+/-1	dB
Output Power (P1 dB)	35.5	dBm
Input Return Loss	9	dB
Output Return Loss	9	dB
Saturated output power (P <sub>sat</sub> )	36.5	dBm
Output Third Order Intercept (IP3)	45	dBm
Power Added Efficiency (PAE)	25%	--
Supply Current(I <sub>dq</sub> )	1.5	A
Supply Current(I <sub>dsat</sub> <sup>2</sup> )	2.1	A

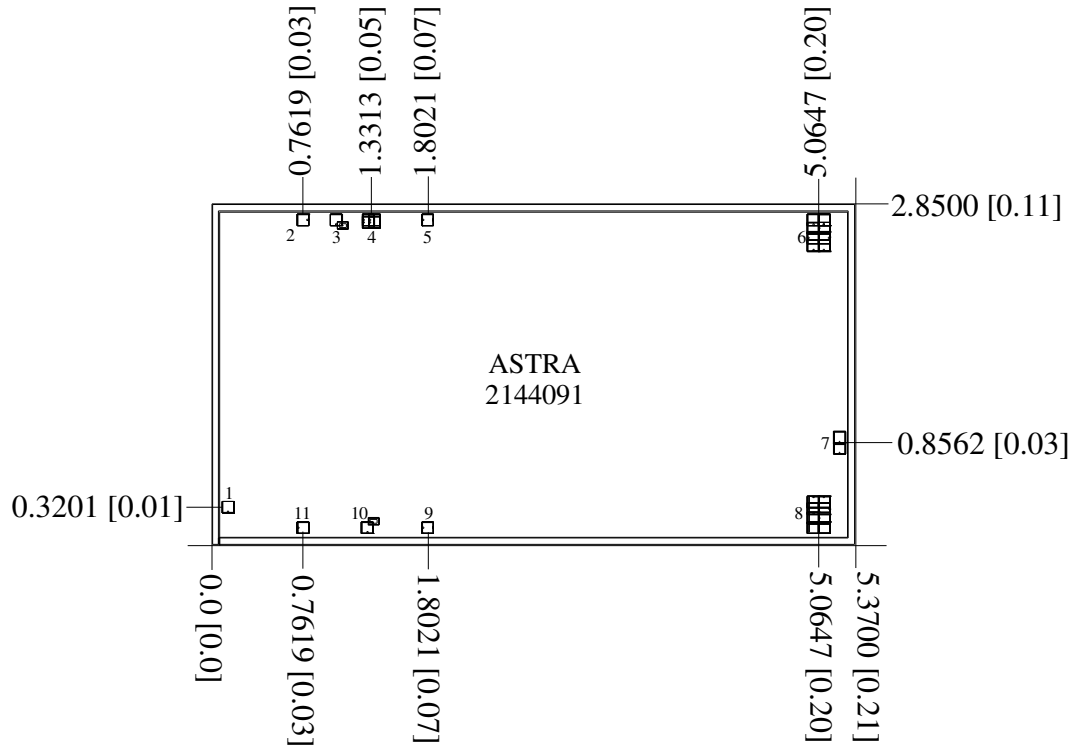
**Note:**

1. Electrical specifications as measured in test fixture.
2. I<sub>dsat</sub> is the maximum drain current under input RF drive condition.

**Test fixture data**
 $V_{d1} = V_{d2} = 8V, V_{g1} = V_{g2} = -1.1V, \text{Total Current } (I_{dq}) = 1.5A, T_A = 25^\circ C$ 


**Test fixture data**
 $V_{d1} = V_{d2} = 8V$ ,  $V_{g1} = V_{g2} = -1.1V$ , Total Current ( $I_{dq}$ ) = 1.5A,  $T_A = 25^\circ C$ 


## Bond Pad Locations

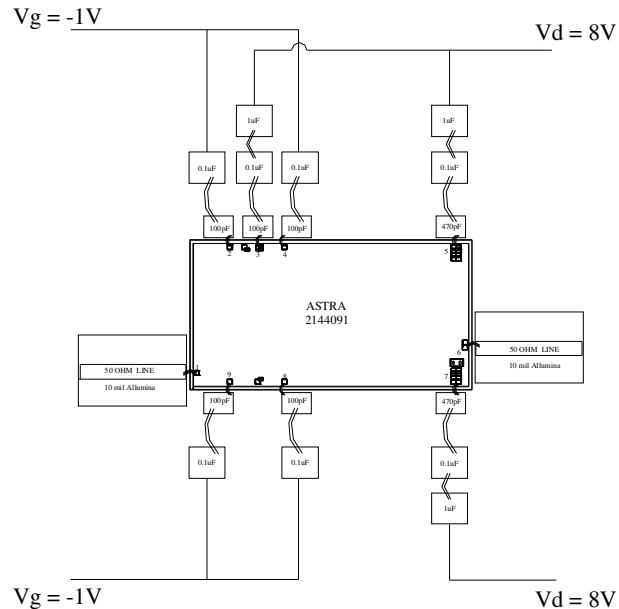


**Units:** millimeters (inches)

**Note:**

1. All RF and DC bond pads are 100 $\mu$ m x 100 $\mu$ m
2. Pad no. 1 : RF IN
3. Pad no. 2,11 : 1<sup>st</sup> stage gate voltage( $V_{g1}$ )
4. Pad no. 7 : RF Output
5. Pad no. 4 : 1<sup>st</sup> stage drain voltage( $V_{d1}$ )
6. Pad no. 5,9 : 2<sup>nd</sup> stage gate voltage( $V_{g2}$ )
7. Pad no. 6,8 : 2<sup>nd</sup> stage drain voltage ( $V_{d2}$ )
8. All the dimensions shown above are measured taking bottom left corner as reference.

## Recommended Assembly Diagram



### Note :

1. Open stub of 4mm length, 0.7mm width and 0.1mm thickness to be placed at output immediate to the chip for proper matching.
2. Two 1 mil (0.0254mm) bond wires of minimum length should be used for RF input and output.
3. Two 1 mil (0.0254mm) bond wires of minimum length should be used from chip bond pad to 100pF capacitor.
4. Input and output 50 ohm lines are on 10 mil Allumina or 5 mil RT Duroid.
5. 100pF, 0.1uF and 1uF bypass capacitors are used as shown above.
6. The RF input & output ports are DC decoupled on-chip.

**Die attach:** For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of fluxless AuSn (80/20) 1-2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

**Wire bonding:** For DC pad connections use either ball or wedge bonds. For best RF performance, use of 150 - 200 $\mu$ m length of wedge bonds is advised. Single Ball bonds of 250-300 $\mu$ m though acceptable, may cause a deviation in RF performance.



***GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing***

All information and Specifications are subject to change without prior notice